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Wide Temperature Range Version 4 M SRAM (512-kword × 8-bit)



ADE-203-1211C (Z) Rev. 3.0 Dec. 18, 2002

Description

The Hitachi HM628512CI is a 4-Mbit static RAM organized 512-kword \times 8-bit. HM628512CI Series has realized higher density, higher performance and low power consumption by employing CMOS process technology (6-transistor memory cell). The HM628512CI Series offers low power standby power dissipation; therefore, it is suitable for battery backup systems. It has packaged in 32-pin SOP, 32-pin TSOP II and 32-pin DIP.

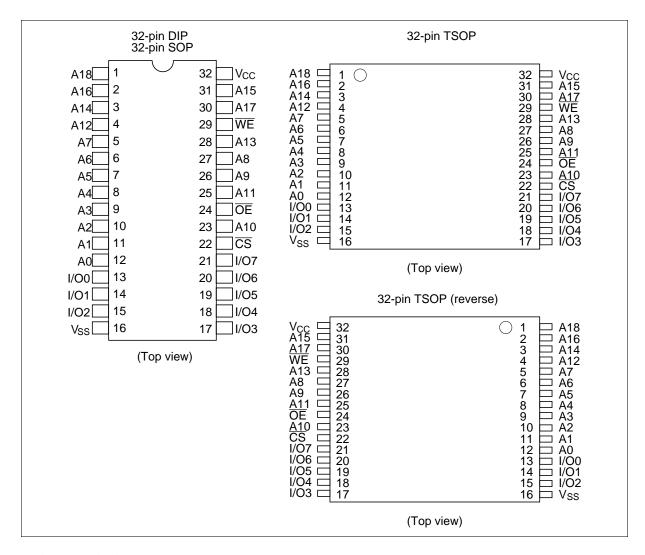
Features

- Single 5 V supply
- Access time: 55/70 ns (max)
- Power dissipation
 - Active: 10 mW/MHz (typ)
 - Standby: 4 μW (typ)
- Completely static memory. No clock or timing strobe required
- Equal access and cycle times
- Common data input and output: Three state output
- Directly TTL compatible: All inputs and outputs
- Battery backup operation
- Operating temperature: -40 to +85°C

Ordering Information

Type No.	Access time	Package
HM628512CLPI-7	70 ns	600-mil 32-pin plastic DIP (DP-32)
HM628512CLFPI-5 HM628512CLFPI-7	55 ns 70 ns	525-mil 32-pin plastic SOP (FP-32D)
HM628512CLTTI-5 HM628512CLTTI-7	55 ns 70 ns	400-mil 32-pin plastic TSOP II (TTP-32D)
HM628512CLRRI-7	70 ns	400-mil 32-pin plastic TSOP II reverse (TTP-32DR)

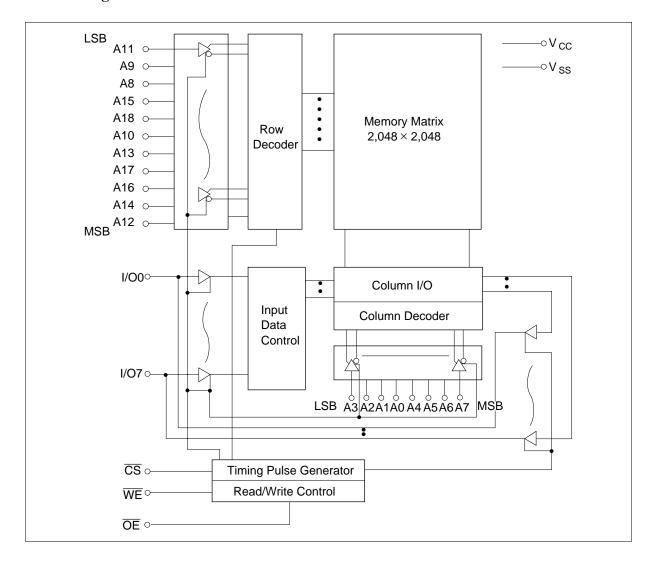
Pin Arrangement



Pin Description

Pin name	Function			
A0 to A18	Address input			
I/O0 to I/O7	Data input/output			
CS	Chip select			
ŌĒ	Output enable			
WE	Write enable			
V _{cc}	Power supply			
V _{SS}	Ground			

Block Diagram



Function Table

WE	CS	OE	Mode	V _{cc} current	Dout pin	Ref. cycle
×	Н	×	Not selected	I_{SB}, I_{SB1}	High-Z	_
Н	L	Н	Output disable	I _{cc}	High-Z	_
Н	L	L	Read	I _{cc}	Dout	Read cycle
L	L	Н	Write	I _{cc}	Din	Write cycle (1)
L	L	L	Write	I _{cc}	Din	Write cycle (2)

Note: x: H or L

Absolute Maximum Ratings

Parameter	Symbol	Value	Unit
Power supply voltage	V _{cc}	-0.5 to +7.0	V
Voltage on any pin relative to V _{ss}	V _T	-0.5^{*1} to $V_{CC} + 0.3^{*2}$	V
Power dissipation	P _T	1.0	W
Operating temperature	Topr	-40 to +85	°C
Storage temperature	Tstg	-55 to +125	°C
Storage temperature under bias	Tbias	-40 to +85	°C

Notes: 1. V_T min: -3.0 V for pulse half-width ≤ 30 ns.

2. Maximum voltage is 7.0 V.

Recommended DC Operating Conditions ($Ta = -40 \text{ to } +85^{\circ}\text{C}$)

Parameter	Symbol	Min	Тур	Max	Unit
Supply voltage	V _{cc}	4.5	5.0	5.5	V
	V _{SS}	0	0	0	V
Input high voltage	V_{IH}	2.4	_	V_{cc} + 0.3	V
Input low voltage	V _{IL}	-0.3 ^{*1}	_	0.6	V

Note: 1. V_{IL} min: -3.0 V for pulse half-width ≤ 30 ns.

DC Characteristics

Parameter	Symbol	Min	Typ*1	Max	Unit	Test conditions
Input leakage current	I _{LI}	_		1	μΑ	$Vin = V_{SS} to V_{CC}$
Output leakage current	I _{LO}	_	_	1	μΑ	$ \overline{CS} = V_{IH} \text{ or } \overline{OE} = V_{IH} \text{ or} \overline{WE} = V_{IL}, V_{I/O} = V_{SS} \text{ to } V_{CC} $
Operating power supply current: DC	I_{cc}	_	1.5	3	mA	$\overline{\text{CS}} = \text{V}_{\text{IL}},$ others = $\text{V}_{\text{IH}}/\text{V}_{\text{IL}}, \text{I}_{\text{I/O}} = 0 \text{ mA}$
Operating power HM628512CI-5 supply current	I _{CC1}	_	8	25	mA	
HM628512CI-7	I _{CC1}	_	7	25	mΑ	
Operating power supply current	I _{CC2}	_	2	5	mA	$\begin{split} & \text{Cycle time} = 1 \; \mu\text{s}, \\ & \text{duty} = 100\% \\ & \text{I}_{\text{I/O}} = 0 \; \text{mA}, \; \overline{\text{CS}} \leq 0.2 \; \text{V} \\ & \text{V}_{\text{IH}} \geq \text{V}_{\text{CC}} - 0.2 \; \text{V}, \; \text{V}_{\text{IL}} \leq 0.2 \; \text{V} \end{split}$
Standby power supply current: DC	I _{SB}	_	0.1	0.5	mA	CS = V _{IH}
Standby power supply current (1): D0	C I _{SB1}	_	0.8*2	20*2	μΑ	$Vin \ge 0 \text{ V}, \overline{CS} \ge V_{CC} - 0.2 \text{ V}$
Output low voltage	V _{OL}			0.4	V	I _{OL} = 2.1 mA
Output high voltage	V _{OH}	2.4	_	_	V	I _{OH} = -1.0 mA

Notes: 1. Typical values are at $V_{cc} = 5.0 \text{ V}$, $Ta = +25^{\circ}\text{C}$ and specified loading, and not guaranteed.

Capacitance (Ta = +25°C, f = 1 MHz)

Parameter	Symbol	Тур	Max	Unit	Test conditions
Input capacitance*1	Cin	_	8	pF	Vin = 0 V
Input/output capacitance*1	C _{I/O}	_	10* ²	pF	V _{I/O} = 0 V

Note: 1. This parameter is sampled and not 100% tested.

2. $C_{I/O}$ max = 12 pF only for HM628512CLPI Series.

AC Characteristics (Ta = -40 to +85 °C, V_{CC} = 5 V \pm 10%, unless otherwise noted.)

Test Conditions

• Input pulse levels: 0.4 V to 2.4 V

• Input rise and fall time: 5 ns

• Input and output timing reference levels: 1.5 V

• Output load: 1 TTL Gate + C_L (50 pF) (HM628512CI-5)

 $1 \text{ TTL Gate} + C_L (100 \text{ pF}) (HM628512CI-7)$

(Including scope and jig)

Read Cycle

		HM628512CI						
		-5		-7				
Parameter	Symbol	Min	Max	Min	Max	Unit	Notes	
Read cycle time	t _{RC}	55	_	70	_	ns		
Address access time	t _{AA}	_	55	_	70	ns		
Chip select access time	t _{co}	_	55	_	70	ns		
Output enable to output valid	t_{OE}	_	25	_	35	ns		
Chip selection to output in low-Z	$t_{\scriptscriptstyle LZ}$	10	_	10	_	ns	2	
Output enable to output in low-Z	t _{oLZ}	5	_	5	_	ns	2	
Chip deselection to output in high-Z	t _{HZ}	0	20	0	25	ns	1, 2	
Output disable to output in high-Z	t_{OHZ}	0	20	0	25	ns	1, 2	
Output hold from address change	t _{oh}	10	_	10	_	ns		

Write Cycle

HM	1628	512	CI
1 117	1020	J 14	-

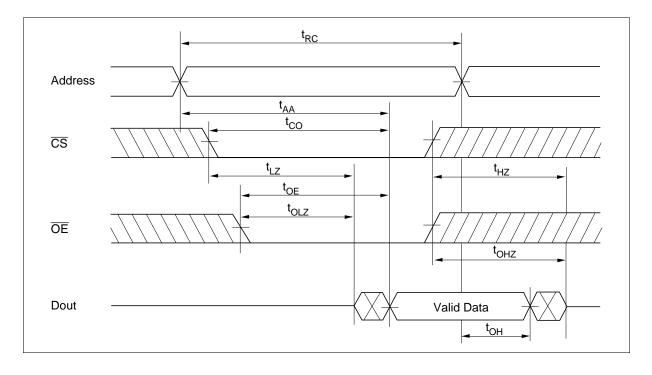
		-5		-7			
Parameter	Symbol	Min	Max	Min Ma		Unit	Notes
Write cycle time	t _{wc}	55	_	70	_	ns	
Chip selection to end of write	t _{cw}	50	_	60	_	ns	4
Address setup time	t _{AS}	0	_	0	_	ns	5
Address valid to end of write	t _{AW}	50	_	60	_	ns	
Write pulse width	t_{WP}	40	_	50	_	ns	3, 12
Write recovery time	t_{WR}	0	_	0	_	ns	6
WE to output in high-Z	t _{whz}	0	20	0	25	ns	1, 2, 7
Data to write time overlap	t _{DW}	25	_	30	_	ns	
Data hold from write time	t _{DH}	0	_	0	_	ns	
Output active from output in high-Z	t _{ow}	5	_	5	_	ns	2
Output disable to output in high-Z	t _{OHZ}	0	20	0	25	ns	1, 2, 7

Notes: 1. t_{HZ} , t_{OHZ} and t_{WHZ} are defined as the time at which the outputs achieve the open circuit conditions and are not referred to output voltage levels.

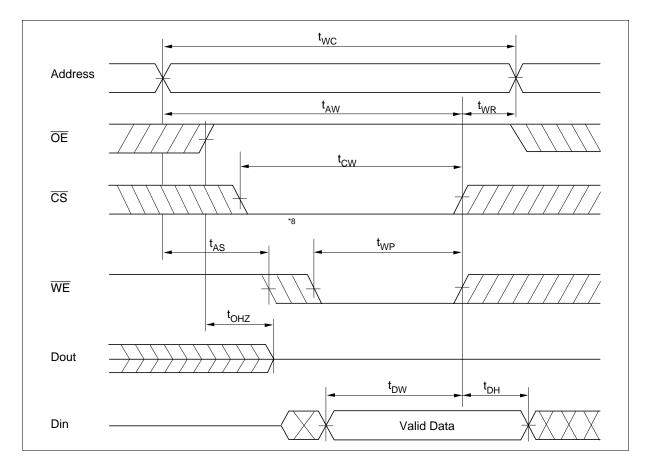
- 2. This parameter is sampled and not 100% tested.
- 3. A write occurs during the overlap (t_{WP}) of a low \(\overline{CS}\) and a low \(\overline{WE}\). A write begins at the later transition of \(\overline{CS}\) going low or \(\overline{WE}\) going low. A write ends at the earlier transition of \(\overline{CS}\) going high or \(\overline{WE}\) going high. t_{WP} is measured from the beginning of write to the end of write.
- 4. t_{CW} is measured from $\overline{\text{CS}}$ going low to the end of write.
- 5. t_{AS} is measured from the address valid to the beginning of write.
- 6. t_{WR} is measured from the earlier of \overline{WE} or \overline{CS} going high to the end of write cycle.
- 7. During this period, I/O pins are in the output state so that the input signals of the opposite phase to the outputs must not be applied.
- 8. If the $\overline{\text{CS}}$ low transition occurs simultaneously with the $\overline{\text{WE}}$ low transition or after the $\overline{\text{WE}}$ transition, the output remain in a high impedance state.
- 9. Dout is the same phase of the write data of this write cycle.
- 10. Dout is the read data of next address.
- 11. If \overline{CS} is low during this period, I/O pins are in the output state. Therefore, the input signals of the opposite phase to the outputs must not be applied to them.
- 12. In the write cycle with \overline{OE} low fixed, t_{WP} must satisfy the following equation to avoid a problem of data bus contention. $t_{WP} \ge t_{DW}$ min + t_{WHZ} max

Timing Waveforms

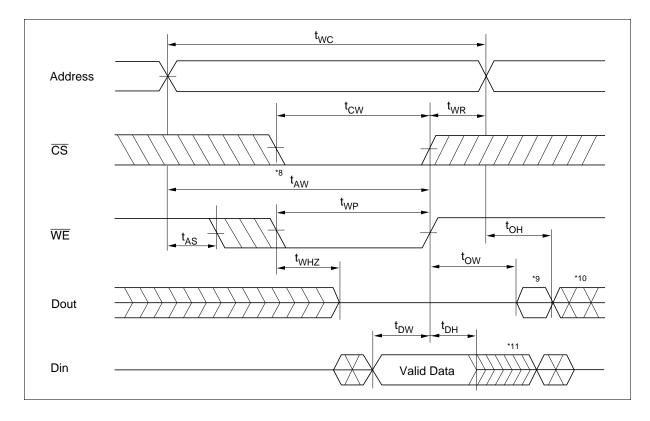
Read Timing Waveform $(\overline{WE}=V_{IH})$



Write Timing Waveform (1) $(\overline{OE} \operatorname{Clock})$



Write Timing Waveform (2) $(\overline{OE} Low Fixed)$



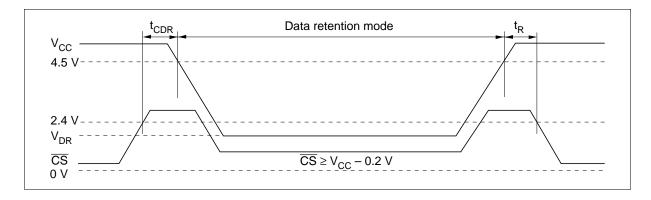
Low V_{CC} **Data Retention Characteristics** ($Ta = -40 \text{ to } +85^{\circ}\text{C}$)

Parameter	Symbol	Min	Тур	Max	Unit	Test conditions*2
V _{cc} for data retention	V_{DR}	2	_	_	V	$\overline{\text{CS}} \ge \text{V}_{\text{CC}} - 0.2 \text{ V, Vin} \ge 0 \text{ V}$
Data retention current	I _{CCDR}	_	0.8*3	20*1	μΑ	$\frac{V_{CC} = 3.0 \text{ V, Vin} \ge 0 \text{ V}}{CS} \ge V_{CC} - 0.2 \text{ V}$
Chip deselect to data retention time	t_{CDR}	0	_	_	ns	See retention waveform
Operation recovery time	t_{R}	t_{RC}^{*4}	_	_	ns	

Notes: 1. $10 \mu A \text{ (max)}$ at $Ta = -40 \text{ to } +40 ^{\circ} C$.

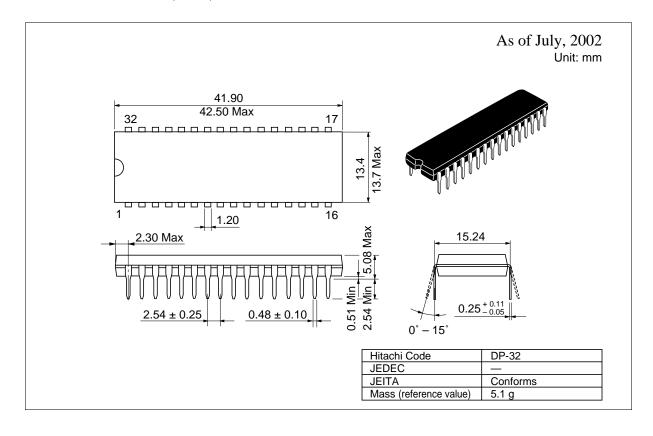
- 2. $\overline{\text{CS}}$ controls address buffer, $\overline{\text{WE}}$ buffer, $\overline{\text{OE}}$ buffer, and Din buffer. In data retention mode, Vin levels (address, $\overline{\text{WE}}$, $\overline{\text{OE}}$, I/O) can be in the high impedance state.
- 3. Typical values are at $V_{\rm CC}$ = 3.0 V, Ta = +25°C and specified loading, and not guaranteed.
- 4. t_{RC} = read cycle time.

$Low~V_{CC}~Data~Retention~Timing~Waveform~(\overline{CS}~Controlled)$



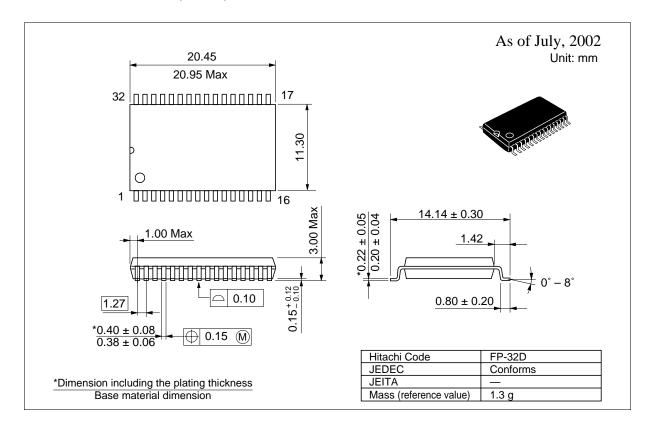
Package Dimensions

HM628512CLPI Series (DP-32)



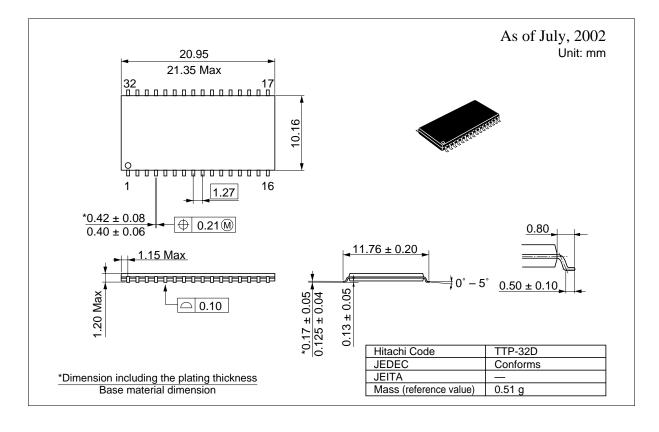
Package Dimensions (cont.)

HM628512CLFPI Series (FP-32D)



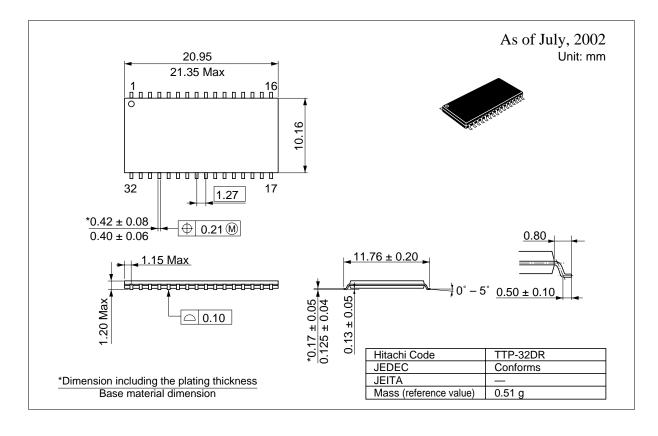
Package Dimensions (cont.)

HM628512CLTTI Series (TTP-32D)



Package Dimensions (cont.)

HM628512CLRRI Series (TTP-32DR)



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